# Emerging Standards for EMC Emissions & Immunity



Requirements for Industrial, Scientific, Medical & Information Technology Equipment

**CE** Marking requirements are the path to increased market access

Powerful Globalization forces will encourage "harmonized" products designed for World markets rather than simply regional markets



# **Overview of Testing Requirements**

	Emissions	Immunity
Conducted	CISPR 11, 22	EN 61000-4-6
Radiated	CISPR 11, 22	EN 61000-4-3
Power-line	Harmonics / Flicker	EN 61000-4-8, -11
E. S. D.		EN 61000-4-2
E.F.T.		EN 61000-4-4
Surge		EN 61000-4-5

# **Emerging Test Requirements:**

(required in 2001)



- EN 61000-4-5 Lightning Strike (Surge) 7/1/01
- EN 61000-4-6 Conducted R.F. Voltages 7/1/01
- EN 61000-4-8 50Hz Magnetic Fields 7/1/01
- EN 61000-4-11 Power line slow variations 7/1/01
- EN 61000-3-2 Power line Harmonics 1/1/01
- EN 61000-3-3 Power line Flicker 1/1/01

EN 55011(98)

EN 55022(98)

EN 55024(98)

- Industrial, Scientific, Medical 1/1/01
- **Computer / Telco emissions 8/1/01**
- **Computer / Telco immunities 7/1/01**



#### Lightning Strike (Surge)



#### **Combination wave definitions**



# Lightning Strike (Surge)



Front time; Time to half-value:  $T_1 = 1.67 \times T = 10 \ \mu s \pm 30 \ \%$  $T_2 = 700 \ \mu s \pm 20 \ \%.$ 

Waveform of open-circuit voltage (10/700  $\mu$ s) (waveform definition according to CCITT)

#### **Telecomm (CCITT) wave definition**



# Lightning Strike (Surge)

0,5
1,0
2.0
4,0
Special

#### **Test levels for Surge testing**



# Lightning Strike (Surge)

#### Installation classes for Surge testing:

Class 0	Well-protected electrical environment, often within a special room
Class 1	Partly protected electrical environment
Class 2	Electrical environment where cables are well separated, even at short runs
Class 3	Electrical environment where cables run in parallel
Class 4	Electrical environment where interconnects are running outdoors, along with power cables, and are used for both electronic and electric circuits
Class 5	Electrical environment with equipment connected to telecommunications lines & overhead power lines in rural areas
Class x	Special conditions specified in the product specification



#### Lightning Strike (Surge)

	Test levels							
Installation class	Power	r supply	Unbalance circuits/I Couplin	ed operated ines, LDB ng mode	Balanceo circui Couplii	d operated ts/lines ng mode	SDB Coupli	, DB <sup>1)</sup> ng mode
	Line to line kV	Line to earth kV	Line to line kV	Line to earth kV	Line to line kV	Line to earth kV	Line to line kV	Line to earth kV
0	NA	NA	NA	NA	NA	NA	NA	NA
1	NA	0,5	NA	0,5	NA	0,5	NA	NA
2	0,5	1,0	0,5	1,0	NA	1,0	NA	0,5
3	1,0	2,0	1,0	2,0 3)	NA	2,0 3}	NA	NA
4	2,0	4,0 <sup>3)</sup>	2.0	4.0 <sup>3)</sup>	NA	2,0 <sup>3)</sup>	NA	NA
5	2)	2)	2,0	4,0 <sup>3)</sup>	NA	4,0 <sup>3)</sup>	NA	NA
x								

1) Limited distance, special configuration, special layout, 10 m to max. 30 m: no test is advised at interconnection cables up to 10 m, only class 2 is applicable.

2) Depends on the class of the local power supply system.

3) Normally tested with primary protection.

Explanation:

- DB = data bus (data line)
- SDB = short-distance bus
- LDB = long-distance bus
- NA = not applicable



# **Conducted R.F. Voltages**

This Standard describes the Conducted Immunity testing requirements for electrical & electronic equipment to continuos interference from intended RF transmitters operating from 150 kHz - 80 MHz. (optional to 230MHz) Amplitude Modulation (AM) is applied during the test to simulate these emitters.

Four coupling methods are outlined in the Standard:

1.Coupler Decoupler Networks (CDN's)
2.Direct Injection (Direct or "S" series CDN's)
3.Electromagnetic Clamp (EM Clamp)
4.Bulk Current Injection (BCI, 150 & 50 ohms)

Each method requires a "calibration" to measure the required drive level for that coupling method, test level, and test setup. This "drive table" is then played back by the Computer (with 80% AM modulation) during the test run, with an appropriate dwell time (usually 3 seconds) at each frequency, and the performance of the Equipment Under Test (EUT) is monitored by the Auxiliary Equipment (AE) for failures.



## **Conducted R.F. Voltages**

When interference is applied, failures can occur in four types:

- Type A No failures are observed
- Type B Unit is upset, recovers when interference is removed
- Type C Unit is upset, requires operator intervention to re-set
- Type D Unit does not recover (damaged)

Frequency range	.15 MHz -	80 MHz
Level	Voltage lev U <sub>e</sub> [dBuV]	vel (e.m.f.) U <sub>e</sub> [V]
1	120	1
2	130	3
3	140	10
X <sup>(1)</sup>	spe	cial

1) X is an open level.



#### **Conducted R.F. Voltages**



Rules for selecting the injection method

The Standard uses a logical decision tree to guide in the choice of coupling method. First, it asks; <u>Are CDN's</u> <u>suitable?</u> If a terminated CDN is inserted into the Power or I/O lines of the EUT, and those lines continue to function, then that CDN should be used on that line.



Note\_\_\_ CDN-M3, C<sub>1</sub>(typ) = 10 nF, C<sub>1</sub>(typ) = 47 nF, R = 300 Ω, L ≥ 280 µH at 150 kHz CDN-M2; C<sub>1</sub>(typ) = 10 nF, C<sub>1</sub>(typ) = 47 nF, R = 200 Ω, L ≥ 280 µH at 150 kHz CDN-M1; C<sub>1</sub>(typ) = 22 nF, C<sub>2</sub>(typ) = 47 nF, R = 100 Ω, L ≥ 280 µH at 150 kHz



#### **Conducted R.F. Voltages**



Rules for selecting the injection method

If a Coupler Decoupler Network (CDN) is not suitable, is the line shielded (screened)? If so, you may use the "S" series CDN if suitable.



"S" series CDN (S-1)



### **Conducted R.F. Voltages**

You may also use Direct Injection (through the R-100) onto the shield (screen) of the cable under test. Separate decoupling with the Ferrite Decoupler is then recommended.



Principle of direct coupling to screened cables.



#### **Conducted R.F. Voltages**



Rules for selecting the injection method

If neither of these methods is suitable, clamp injection techniques are allowed. However, injected currents must be monitored with a monitor current probe and Spectrum Analyzer for both the BCI probe (150 & 50 ohms) as well as for the EM Clamp (150 ohms) methods. The use of a Ferrite Decoupler to protect the AE is recommended for both clamp injection techniques. The test setup shall present the 150 ohm common mode impedance required in Paragraph 6.2 and the functional installation conditions as closely as possible.



#### **Conducted R.F. Voltages**



Example of Clamp injection methods (EM Clamp or BCI)



#### **Conducted R.F. Voltages**



**Example of EM Clamp construction** 



#### **Conducted R.F. Voltages**



Rules for selecting the injection method

To ensure the 150 ohm common mode impedance is realized, check that the following conditions of 7.2 are met:

- Each AE is placed on a 100mm support above the ground plane
- All cables touching each AE shall be provided with a Ferrite Decoupler and kept 30-50mm above the ground plane
- Cable lengths are kept short (< 0.3M)
- Terminated CDN's are used on all other AE power & I/O lines



#### **Conducted R.F. Voltages**



Rules for selecting the injection method

If one or more of these conditions cannot be met, it is necessary to ensure that the common mode impedance of the AE is less than or equal to the common mode impedance of the EUT port being tested. If not, measures must be taken to lower this AE impedance, such as decoupling capacitors at the AE port, etc. Check that the following conditions are met:

- Each AE and EUT shall be installed in a typical, functional way
- The injected current shall be monitored to ensure never exceeding I (max) which equals V(emf)/150 ohms.



#### **Conducted R.F. Voltages**



Test Level:

**Meter Reading:** 

1 volt (emf) (120dBuV) - (15.6dB) - (107dB) = -2.6dBm

3 volt (emf) (130dBuV) - (15.6dB) - (107dB) = 7.4dBm

10 volt (emf) (140dBuV) - (15.6dB) - (107dB) = 17.4dBm

The frequency is incremented in 1% steps, and the drive level out of the Signal Generator (dBm) is adjusted to give the Power Meter readings shown above. This becomes the "drive table" played back by the Computer during the test run.



#### **Conducted R.F. Voltages**

CDN Run-test setup



After completion of the "drive table," disconnect the Calibration Adapters from the CDN, and connect it into the test setup as shown. Notice that the EUT is elevated 100mm above the ground plane, and all EUT ports are to be fitted with terminated CDN's. The "drive table" is played back by the Computer with 80% AM modulation, and the EUT is monitored for failures.



#### **Conducted R.F. Voltages**





#### **Conducted R.F. Voltages**



NOTE: In many cases, an "S" Series CDN may be used for Direct Injection. If these are not appropriate, the R-100 and Ferrite Decoupler may be used as shown.

After completion of the "drive table," disconnect the Calibration Adapters from the "S" series CDN or R-100, and connect it into the test setup as shown. Notice that the EUT is elevated 100mm above the ground plane, and all EUT ports are to be fitted with terminated CDN's. The "drive table" is played back by the Computer with 80% AM modulation, and the EUT is monitored for failures.



**Meter Reading:** 

#### **Conducted R.F. Voltages**

**Test Level:** 



1 volt (emf) (120dBuV) - (15.6dB) - (107dB) = -2.6dBm3 volt (emf) (130 dBuV) - (15.6 dB) - (107 dB) = 7.4 dBm10 volt (emf) (140dBuV) - (15.6dB) - (107dB) = 17.4dBm The frequency is incremented in 1% 50 ohm steps, and the drive level out of the Signal Generator (dBm) is adjusted to give the Power Meter readings shown above. This becomes the "drive table" played back by the Computer during the test run.



#### **Conducted R.F. Voltages**

EM Clamp run-test setup



After completion of the "drive table," disconnect the Calibration Adapters from the EM Clamp, and connect it into the test setup as shown. Notice that the EUT is elevated 100mm above the ground plane, and all EUT ports are to be fitted with terminated CDN's. The "drive table" is played back by the Computer with 80% AM modulation, and the EUT is monitored for failures. During the test, the injected current is monitored with a monitor current probe and Spectrum Analyzer to ensure that I (max) is never exceeded.



**Meter Reading:** 

#### **Conducted R.F. Voltages**

**Test Level:** 



1 volt (emf) (120dBuV) - (15.6dB) - (107dB) = -2.6dBm3 volt (emf) (130dBuV) - (15.6dB) - (107dB) = 7.4dBm 10 volt (emf) (140dBuV) - (15.6dB) - (107dB) = 17.4dBm The frequency is incremented in 1% steps, and the drive level out of the Signal Generator (dBm) is adjusted to give the Power Meter readings shown above. This becomes the "drive table" played back by the Computer during the test run.



#### **Conducted R.F. Voltages**



After completion of the "drive table," disconnect the Calibration Adapters from the BCI probe, and connect it into the test setup as shown. Notice that the EUT & AE are elevated 100mm above the ground plane, and all EUT ports are to be fitted with terminated CDN's. The "drive table" is played back by the Computer with 80% AM modulation, and the EUT is monitored for failures. During the test, the injected current is monitored with a monitor current probe and Spectrum Analyzer to ensure that I (max) is never exceeded.



#### **Conducted R.F. Voltages**



Test Level: Meter Reading:

1 volt (emf)

(120dBuV) - (6 dB) - (107dB) = +7.0dBm

3 volt (emf) (130dBuV) - (6 dB) - (107dB) = +17.0dBm

10 volt (emf) (140dBuV) - (6 dB) - (107dB) = +27.0dBm

The frequency is incremented in 1% steps, and the drive level out of the Signal Generator (dBm) is adjusted to give the Power Meter readings shown above. This becomes the "drive table" played back by the Computer during the test run.



#### **Conducted R.F. Voltages**



After completion of the "drive table," disconnect the Calibration Adapters from the BCI probe, and connect it into the test setup as shown. Notice that the EUT & AE are elevated 100mm above the ground plane, and all EUT ports are to be fitted with terminated CDN's. The "drive table" is played back by the Computer with 80% AM modulation, and the EUT is monitored for failures. During the test, the injected current is monitored with a monitor current probe and Spectrum Analyzer to ensure that I (max) is never exceeded.



# **50Hz Magnetic Fields**

This Standard is intended to demonstrate the immunity of equipment subjected to power frequency magnetic fields related to its specific location and installation conditions. These fields are generated by currents flowing in nearby conductors or transformers near the equipment.

The Standard differentiates between:

• Current under normal operating conditions, producing steady magnetic fields with relatively small amplitudes;

• Current under fault conditions, which can produce relatively high magnetic fields of short duration, until the protection devices operate

Steady magnetic fields apply to all types of equipment.

<u>Short-duration</u> magnetic fields are related to fault conditions, with the highest values applying to equipment installed in electrical plants.



#### **50Hz Magnetic Fields**

Test levels for continuous field

Test levels for short duration: 1 to 3 s.

Levei	Magnetic field strength A/m	Level	Magnetic field strength A/m
1	1	1	n.a. <sup>2)</sup>
2	3	2	n.a. <sup>2)</sup>
3	10	3	n.a. <sup>2)</sup>
4	30	4	300
5	100	5	1000
x <sup>1)</sup>	special	x <sup>1)</sup>	special

#### NOTES

1 - "x" is an open level. This level, as well the duration of the test for short duration field, can be given in the product specification.

2 - "n.a." = not applicable

#### Severity Levels: 10 dB steps (1A/m=1.26uT)



## **50Hz Magnetic Fields**

#### **Selection of the test levels**

- Class 1: Sensitive electron-beam devices are used, like monitors or electron microscopes
- Class 2: Well-protected environment like households, offices, or hospital protected areas
- Class 3: Protected environment like commercial, light industrial or control buildings

#### Class 4: Typical industrial environment or power control room

#### Class 5: Severe industrial environment or switchyard areas

#### Class x: Special environment, higher or lower than those above



#### **50Hz Magnetic Fields**



- Vr: Voltage regulator
- C: Control circuit
- Tc: Current transformer

Schematic circuit of the test generator for power frequency magnetic field.



#### **50Hz Magnetic Fields**



Test set-ups for floor-standing and table-top equipment



#### **50Hz Magnetic Fields**



Figure B.3 - 3 dB area of the field generated by a square induction coil (1 m side) in the mean orthogonal plane (component orthogonal to the plane of the coil).



Figure B.5 - 3 dB area of the field generated by two square induction colls (1 m side) 0.8 m spaced, in the mean orthogonal plane (component orthogonal to the plane of the colls).

#### Field Uniformity (3dB) for single & double induction coils

#### NOTE:

#### A uniform field <u>cannot be generated</u> over a GRP when the coil is within 50cm of GRP.



# Field Uniformity (3dB) for single induction coil with GRP return



# **50Hz Magnetic Fields**

#### Magnetic field calibration:

The <u>voltage delivered</u> from the AC Power Source (and <u>hence the current</u> in the induction coil) is adjusted to calibrate the magnetic field in the center of the coil.

A narrow-band instrument with a small multi-turn loop or "Hall Effect" sensor is employed to calibrate the "induction factor" of the coil. (H/A or Field Strength / Current) The AC Power Source can be programmed to deliver the corresponding voltages for Continuos and Short-term tests.

#### **Standard induction coils:**

- Single square (1M x 1M) test volume (EUT) = 0.6 x 0.6 x 0.5H
- Double square, 0.6M separation test volume = 0.6 x 0.6 x 1H
- Double square, 0.8M separation test volume = 0.6 x 0.6 x 1.2H
- Single rectangular (1M x 2.6M) test volume = 0.6 x 0.6 x 2H



# Voltage dips, interrupts & variations

#### Scope:

This Standard defines the immunity test methods and levels for electrical & electronic equipment connected to the low-voltage mains for voltage dips, short interruptions, and voltage variations. It applies to all electrical & electronic equipment with rated input currents of 16 AMPS per phase, single or three-phase. (excludes DC or 400Hz networks)

Voltage dips and interruptions are caused by faults in the network or installation, or by sudden, large changes in load. These phenomena are random and not always abrupt.

Voltage dips simulate the effects of sudden voltage change. Rotating machines can act as generators when spinning down and prevent rapid voltage changes in some installations, hence the voltage variation tests use gradual changes in voltage.



#### Voltage dips, interrupts & variations

Preferred test levels and durations for voltage dips and short Interruptions

Test level % UT	Voitag <del>e</del> Dip/int %U <sub>T</sub>	Duration (in period)
0	100	0,5*
40	60	1 5 10 25 50
70	30	X

\* For 0.5 period, test shall be made in positive and negative polarity, i.e. starting at 0° and 180° respectively.

Notes:

- 1) One or more of the above test levels and durations may be chosen,
- 2) If the EUT is tested for voltage dips of 100 %, it is generally unnecessary to test for other levels for the same durations. However, for some cases (safeguard systems or electromechanical devices) it is not true. The product specification or product committee shall give an indication of the applicability of this note.
- 3) 'x' is an open duration. This duration can be given in the product specification. Utilities in Europe have measured dips and short interruptions of duration between 1/2 a penod and 3000 periods, but duration less than 50 periods are most common.

4) Any duration may apply to any test level.



### Voltage dips, interrupts & variations



Voitage dips test

Note: The voltage decrease to 70% for 10 periods. Step at zero crossing



#### Voltage dips, interrupts & variations

Timing of short term supply voltage variations

Voltage Test Level	Time for decreasing voltage	Time at reduced voltage	Time for increasing vottage
40 % UT	2 s ± 20 %	1 s ± 20 %	2 s ± 20 %
0 % UT	2 s ± 20 %	1 s ± 20 %	2 s ± 20 %
	×	X	×

Note: x represents an open set of durations and can be given in the product specification.



#### Voltage dips, interrupts & variations



- NOTE La tension d'essai diminue graduellement
- NOTE The voltage gradually decreases.





## Voltage dips, interrupts & variations

#### **Power source requirements:**

The generator peak inrush capability is verified using a bridge rectifier, R-C load and current probe.

The maximum inrush of the EUT is also verified with the same current probe, and shall not exceed 70% of the measured inrush drive capability of the generator.



Figure A.1 – Circuit for determining the inrush current drive capability of the short interruptions generator





## Voltage dips, interrupts & variations

Output current capability of 16 A r.m.s. per phase at rated voltage. The generator should supply 23 A at 70% of rated voltage, and 40 A at 40% of rated voltage for a duration of up to 5 seconds.

Variable transformer Phase Phase Controlle Switch Power supply Power supply Power amplifie Switch 2 Wave-lon Voltmeter Voltmete FUT EUT nonorator oscilloscopi oscilloscope Variable transformer Neutral o IEC SUM IEC 38 Figure C.1 a - Schematic of test instrumentation for voltage dips and Figure C.1 b - Schematic of test instrumentation for voltage dips, short interruptions using variable transformers and switches short interruptions and variations using power amplifier

Voltage change at 100% output (0-16A) < 5%

Voltage change at 70% output (0-23A) < 7%

Voltage change at 40% output (0-40A) < 10%

Abrupt load change rise (fall) time with 100 ohm load: 1uS - 5uS



# **Harmonic Current Emissions**

This Standard applies to electrical & electronic equipment drawing up to 16 Amps per phase from the public low-voltage distribution system.



**Classification of Equipment** 

Class A: Balanced 3-phase & all other equipment not classified below

**Class B: Portable tools** 

**Class C: Lighting equipment & dimmers** 

Class D: "Special wave shape" equipment

Figure 2 - Flow-chart for the classification of equipment



# **Harmonic Current Emissions**



Figure 1 – Envelope of the input current to define the "special wave shape" and to classify equipment as Class D

Whatever their wave shape, Class B(tools), Class C(lighting) or motordriven equipment with phase angle control are not considered Class D equipment.



#### **Harmonic Current Emissions**

Table 1 - Limits for Class A equipment

Harmonic order	Maximum permissible harmonic current
n	A
H bbO	narmonics
3	2,30
5	1,14
7	0,77
8	0,40
11	0,33
13	0,21
15 ≤ n ≤39	0,15 <u>15</u> n
Even	harmonics
2	1,08
4	0,43
6	0,30
8 ≤ n ≤ 40	0,23 <u>8</u>

Class B limits: multiply values above by 1.5 for harmonic current limits



#### **Harmonic Current Emissions**

Table 2 – Limits for Class C equipment

Harmonic order	Maximum permissible harmonic currrent expressed as a percentage of the input current
n	at the fundamental frequency %
2	2
3	30 · X *
5	10
7	7
ê	5
11 ≤ n <u>≤</u> 39	3
(odd harmonics only)	
* $\lambda$ is the circuit power factor	مي <u>المعالم المعالم الم</u>

#### Table 3 – Limits for Class D equipment

Harmonic order	Maximum permissible harmonic current per watt	Maximum permissible harmonic current
·····	EUA/ VY	^
3	3,4	2,30
5	1,9	1,14
7	1,0	0,77
9	0,5	0,40
11	0,35	0,33
13 ≤ n ≤ 39 (odd harmonics only)	<u>3,85</u> n	See table 1

Class C limits for lighting equipment

#### Class D limits for "Special wave shape"



#### Harmonic Current Emissions

1000-3-2 © IEC:1995

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s power supply source

- м measurement equipment
- EUT equipment under test
- U test voltage

- Ζ, input impedance of measurement equipment
- z internal impedance of the supply source
  - harmonic component of order n of the line current
- ۱ Ĝ open-loop voltage of the supply source

#### NOTES

1  $Z_s$  and  $Z_\mu$  are not specified, but have to be sufficiently low to suit the test requirements. For the value of  $Z_\mu$ , see annex B.2 b).

2 In some special cases, particular care may be necessary to avoid resonance between the internal inductance of the source and the capacitances of the equipment under test.

Figure A.1 - Measurement circuit for single-phase equipment



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s power supply source

- M measurement equipment
- EUT equipment under test
- G open-loop voltage of the supply source input impedance of the measurement equipment
- Z, internal impedance of the supply source
- Z, harmonic component of order of the line current 4
- υ test voltage (shown as an example between phases L1 and L2)

#### NOTES

1  $Z_{\rm u}$  and  $Z_{\rm u}$  are not specified, but have to be sufficiently low to suit the test requirements. For the value of  $Z_{\rm u}$ , see annex B.2b).

2 In some special cases, particular care may be necessary to avoid resonance between the internal inductance of the source and the capacitances of the equipment under test.

Figure A.2 - Measurement circuit for three-phase equipment



# **Harmonic Current Emissions**

#### **General Test Conditions:**

For equipment not covered, set controls for maximum harmonic currents.

#### **Specific Test Conditions:**

If possible, use the Test Conditions below for:

TV Receivers	Audio Amplifiers	Video Cassette Recorder
Lamps	Luminaires	Ballasts & converters
Lamp Dimmers	Vacuum cleaners	Washers & Dryers
Microwave ovens	Computers	Induction heaters



# Voltage Fluctuations & Flicker Emissions

This Standard applies to electrical & electronic equipment drawing up to 16 Amps per phase from the public low-voltage distribution system. (220 - 250 VAC - 50Hz L-N)

Short-term Flicker Pst is the flicker severity evaluated over a short period (about ten minutes); where Pst = 1 is the conventional threshold of irritability.

Long-term Flicker Plt is the flicker severity evaluated over a long period (about two hours); using successive Pst values.



#### Voltage Fluctuations & Flicker Emissions

1000-3-3 © IEC:1994

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EUT equipment under test

M measuring equipment

S supply source consisting of the supply voltage generator G and reference impedance Z with the elements:

R <sub>A</sub> = 0,24 Ω;	<i>jX<sub>A</sub></i> = 0,15 Ω at 50 Hz;
A <sub>N</sub> = 0,16 Ω;	$jX_{\rm N}$ = 0,10 $\Omega$ at 50 Hz.

The elements include the actual generator impedance.

When the source impedance is not well defined, see 6.2

G voltage source in accordance with 6.3.

NOTE - In general, three-phase loads are balanced, and  $R_{\rm N}$  and  $X_{\rm N}$  can be neglected, as there is no current in the neutral wire.

Figure 1 – Reference network for single-phase and three-phase supplies derived from a three-phase, four-wire supply

**Power Source Requirement:** Z<sub>A</sub>= 0.24 +j 0.15 ohms @ 50 Hz Z<sub>N</sub>= 0.16 +j 0.10 ohms @ 50 Hz

(actual R-L network to IEC 725)



### Voltage Fluctuations & Flicker Emissions

1000-3-3 © IEC:1994







Figure 4 – Curve for  $P_{si}=1$  for rectangular equidistant voltage changes



#### Voltage Fluctuations & Flicker Emissions

1000-3-3 © IEC:1994

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Figure 2 – Histogram evaluation of U(t)



# Voltage Fluctuations & Flicker Emissions

#### **Specific Test Conditions:**

If possible, use the specific Test Conditions below for:

Cookers	Hot Plates	Baking Ovens
Grills	Combinations	Microwave Ovens
Lighting Equipment	Washing machines	Tumbler Dryers
Refrigerators	Copiers, laser printers	Vacuum cleaners
Food mixers	Portable tools	Hairdryers
Consumer Electronics	Water heaters	



#### **Computer & Telecoms Emissions**

#### Changes in the new CISPR 22 (EN55022-1998):



Testing to 1GHz independent of internal clock speeds

#### LISN's used on Power lines

#### ISN's are used on I/O lines

CISPR 22 @ iEC:1997



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AE -- Associated equipment EUT - Equipment uncertest

Figure D.2 – ISN with high longitudinal conversion toas for use with two unscreened single balanced pairs



#### **Computer & Telecoms Emissions**

#### **ISN Specifications:**

Common-mode Z = 150 ohms / 0 deg.

**Common-mode isolation = 35-55dB** 

Longitudinal conversion loss = 80dB

CAT-3 cabling:	50-25dB
CAT-5 cabling:	60-35dB
other	80-55dB

Isolation protects from peripheral noise

**Conversion loss expresses ISN balance** 



Figure D.3 – ISN for use with two unscreened single balanced pairs



AE = Associated equipment EUT = Equipment under test Figure D.4 - ISN for use with two unscreened single balanced pairs



## **Computer & Telecoms Emissions**

**Telecom port:** 

Any analog or digital lines connecting to the telecom network, including LAN ports.

**Common mode emissions:** 

Limits on voltage or current are frequency-dependent

Class A:	>5mV	>32uA	
Class B:	>1.6mV	>10uA	



#### **Computer & Telecoms Emissions**

#### 5.2 Limits of conducted common mode (asymmetric mode) disturbance at telecommunication ports 1)

Table 3 – Limits of conducted common mode (asymmetric mode) disturbance at telecommunication ports in the frequency range 0,15 MHz to 30 MHz for class A equipment

Frequency range	Voltage limits dB (µV)		Current limits dB (µA)	
MHz	Quasi-peak	Average	Quasi-peak	Average
0,15 to 0,5	97 to 87	84 to 74	53 to 43	40 to 30
0,5 to 30	87	74	43	30

NOTE 1 - The limits decrease linearly with the logarithm of the frequency in the range 0,15 MHz to 0,5 MHz.

NOTE 2 – The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150  $\Omega$  to the telecommunication port under test (conversion factor is 20 log<sub>10</sub> 150 / I = 44 dB).

#### Class A commonmode emissions

 

 Table 4 – Limits of conducted common mode (asymmetric mode) disturbance at telecommunication ports in the frequency range 0,15 MHz to 30 MHz for class B equipment

Frequency range	Voltage limits dB (μV)		Current limits dB (µA)	
MHz	Quasi-peak	Average	Quasi-peak	Average
0,15 to 0,5	84 to 74	74 to 64	40 to 30	30 to 20
0,5 to 30	74	64	30	20

#### NOTE 1 - The limits decrease linearly with the logarithm of the frequency in the range 0,15 MHz to 0,5 MHz.

NOTE 2 – The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150  $\Omega$  to the telecommunication port under test (conversion factor is 20 log<sub>10</sub> 150 / 1 = 44 dB).

NOTE 3 - Provisionally, a relaxation of 10 dB over the frequency range of 6 Mhz to 30 Mhz is allowed for high-speed services having significant spectral density in this band. However, this relaxation is restricted to the common mode disturbance converted by the cable from the wanted signal. The provisional relaxation of 10 dB will be reviewed no later than three years after the date of withdrawal based on the results and interference cases seen in this period. Wherever possible it is recommended to comply with the limits without the provisional relaxation.

#### Class B commonmode emissions



#### **Computer & Telecoms Emissions**

#### CDN's from EN61000-4-6 used as ISN's:



- EUT = Equipment under test
- ŋ, Distance to the reference groundplane (vertical or horizontal).
- 2) Distance to the reference groundplane is not onlical.





#### **Computer & Telecoms Emissions**

#### **Combination current & voltage probe:**





#### **Computer & Telecoms Emissions**

#### Measurement of common mode impedance:

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CISPR 22 @ (EC:1997(E)



#### C.2 Measurement of cable, ferrite and AE common mode impedance



#### **Computer & Telecoms Emissions**

#### **Capacitive Voltage Probe in a fixture:**



#### Measurement setup for telecoms:





Fig. A.10 Measurement setup of telecommunication line.



IEC 1 272/07

#### **Computer & Telecoms Emissions**



I/O cables to remote peripherais and/or auxiliary equipment. These cables may be terminated, if required, with correct impedance



#### **Computer & Telecoms Emissions**



# Emerging Standards for EMC Emissions & Immunity



#### Requirements for Industrial, Scientific, Medical & Information Technology Equipment

	Emissions	Immunity
Conducted	CISPR 11, 22	EN 61000-4-6
Radiated	CISPR 11, 22	EN 61000-4-3
Power-line	Harmonics / Flicker	EN 61000-4-8, -11
E. S. D.		EN 61000-4-2
E.F.T.		EN 61000-4-4
Surge		EN 61000-4-5

**Conclusion:** begin pre-testing now to ensure conformity in 2001

# Emerging Standards for EMC Emissions & Immunity



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**Implementation Dates - Paul Rostek, NCR** 

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